

2A Single Input I²C, Standalone Switch-Mode Li-Ion Battery Charger with Integrated Current Sense Resistor

Check for Samples: bq24257, bq24258

FEATURES

- High-efficiency Switch-mode Charger with Integrated Current Sense Resistor
- BC1.2 D+/D– Detection with Dead Battery Provision (DBP) Pin to Sync with External USB-PHI
- USB Charging Compliant
 - Selectable Input Current Limit of 100 mA, 150 mA, 500 mA, and 900 mA.
- In Host Mode (after I²C[™] Communication and Before Watchdog Timer Times Out)
 - Programmable Battery Charge Voltage (V_{BATREG})
 - Programmable Battery Charge Current (I_{CHG})
 - Programmable Input Current Limit (I_{LIM})
 - Programmable Input Voltage Based Dynamic Power Management Threshold (V_{IN_DPM})
 - Programmable Input Overvoltage Protection Threshold (V_{OVP})
 - Programmable Safety Timer.
- In Standalone Mode (before l²C[™] Communication and After Watchdog Timer Times Out)
 - Resistor Programmable I_{CHG} up to 2 A With Current Monitoring Output (I_{SET})
 - Resistor Programmable I_{LIM} up to 2 A With Current Monitoring Output (I_{LIM})
 - Resistor Programmable V_{IN_DPM} (VDPM)

- Watchdog Timer with Disable Bit
- Integrated 4.9 V, 50 mA LDO
- Complete System Level Protection
 - Input UVLO, Input Overvoltage Protection (OVP), Battery OVP, Sleep Mode, V_{IN DPM}
 - Input Current Limit
 - Charge Current Limit
 - Thermal Regulation and Thermal Shutdown
 - Voltage Based, JEITA Compatible NTC Monitoring Input
 - Safety Timer
- 20 V Maximum Input Voltage Rating
- 10.5 V Maximum Operating Input Voltage
- Low R_{DS(on)} Integrated Sense Resistor for up to 2 A Charging Rate
- Open Drain Status Outputs
- Synchronous Fixed-frequency PWM Controller
 Operating at 3 MHz for Small Inductor Support
- AnyBoot Robust Battery Detection Algorithm
- Charge Time Optimizer for Improved Charge
 Times at any Given Charge Current

APPLICATIONS

- Mobile Phones, Smart Phones
- MP3 Players
- Handheld Devices
- Portable Media Player

DESCRIPTION

The bq24257 is a highly integrated single-cell Li-lon battery charger with integrated current sense resistor targeted for space-limited, portable applications with high capacity batteries. The single cell charger has a single input that operates from either a USB port or AC wall adapter for a versatile solution. BC1.2 compliant D+/D-detection allows for recognition of CDP, DCP, SDP, and non-standard USB adapters. The use of an accessory dead battery provision (DBP) pin allows for the system to sync a dead battery state in order to enable/disable the BC1.2 detection in the case of an external USB-PHI.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

All other trademarks are the property of their respective owners.





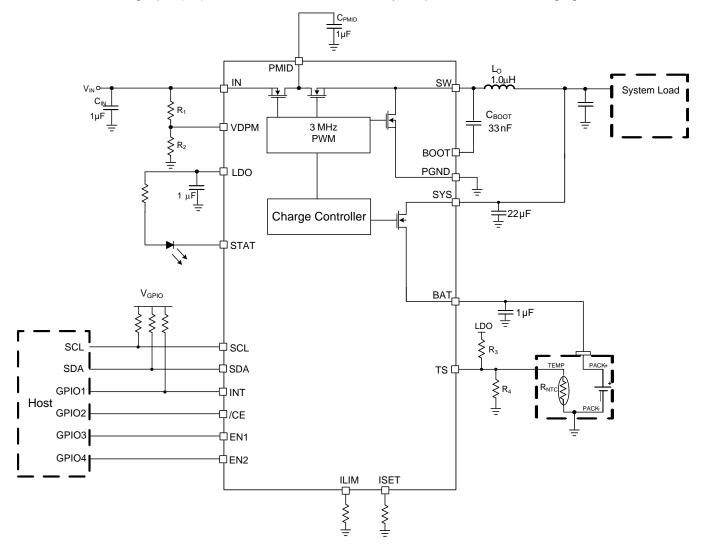
These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DESCRIPTION CONTINUED

The bq24257 has two modes of operation: 1) I2C mode, and 2) Standalone mode. In I2C mode, the host can adjust the charge parameters and monitor the status of the charger operation. In Standalone mode, the external resistor sets the input current limit, charge current limit, and the input DPM level. This mode also serves as the default settings when a DCP adapter is present. The bq24257 enters host mode while the I2C registers are accessed and the watchdog timer has not expired (if enabled).

The bq24258 has only one mode of operation which is the Standalone. In this mode, the external resistor sets the input current limit, charge current limit, and the input DPM level. This mode also serves as the default settings when a DCP adapter is present. The EN1, EN2, and EN3 pin is available in the bq24258 spin to support USB 3.0 compliance.

The battery is charged in four phases: trickle charge, pre-charge, constant current and constant voltage. In all charge phases, an internal control loop monitors the IC junction temperature and reduces the charge current if the internal temperature threshold is exceeded. Additionally, a voltage-based, JEITA compatible battery pack thermistor monitoring input (TS) is included that monitors battery temperature for safe charging.





bq24257 bq24258 SLUSBG0A – FEBRUARY 2013 – REVISED MARCH 2013

AVAILABLE OPTIONS

Device	Default OVP	D+/D– or EN1, EN2, EN3	Default V _{OREG}	VLOWV	TS or DBP	Termination ⁽¹⁾	Chem	i2c	Addr	Default USB ILIM
bq24257	6.5V	D+/D-	3.6V	3.0V	TS	10%	Li / LiPo	Yes	0x6A	100mA
bq24258	10.5	EN1, EN2, EN3	4.2V	3.0V	TS	10%	LiFePO ₄	No	0x6A	N/A ⁽²⁾

(1) Default behavior unless changed via i2C.

(2) Selectable via the EN1, EN2, EN3 pins.

	ORDERING INFORM	ATION
--	------------------------	-------

Part Number ⁽¹⁾	IC Marking	Package	Ordering Number	Quantity
		DSBGA-YFF	bq24257YFFR	3000
h = 0.4057	h = 0.4057	DSBGA-YFF	bq24257YFFT	250
bq24257	bq24257	QFN-RGE	bq24257RGER	3000
		QFN-RGE	bq24257RGET	250
		DSBGA-YFF	bq24258YFFR	3000
h=04050	h = 0.4050	DSBGA-YFF	bq24258YFFT	250
bq24258	bq24258	QFN-RGE	bq24258RGER	3000
		QFN-RGE	bq24258RGET	250

(1) This product is RoHS compatible, including a lead concentration that does not exceed 0.1% of total product weight, and is suitable for use in specified lead-free soldering processes. In addition, this product uses package materials that do not contain halogens, including bromine (Br) or antimony (Sb) above 0.1% of total product weight. SLUSBG0A - FEBRUARY 2013 - REVISED MARCH 2013



www.ti.com

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
	IN	-1.3	20	V
Pin voltage range (with respect	SW	-0.7	12	V
to PGND)	PMID, BOOT	-0.3	20	V
	CSIN, BAT, DPB, LDO, SCL, SDA, STAT, D+, D-, CE, ISET, ILIM, VDPM	-0.3	7	V
BOOT relative to SW	BOOT relative to SW			
Output Current (Continuous) IN, SW, CSIN, BAT			2	А
Output Sink Current	STAT		5	mA
Operating free-air temperature ra	-40	85	°C	
Junction temperature, TJ				°C
Storage temperature, TSTG	-65	150	°C	
Lead temperature (soldering, 10		300	°C	
ESD Rating human body model	2)		2	kV

Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
 The human body model is a 100-pF capacitor discharged through a 1.5-kΩ resistor into each pin.

All voltages are with respect to PGND if not specified. Currents are positive into, negative out of the specified terminal. Consult Packaging Section of the data book for thermal limitations and considerations of packages.

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNITS
V	IN voltage range	4.35	18 ⁽¹⁾	V
V _{IN}	IN operating voltage range	4.35	10.5	
I _{IN}	Input current		2	А
I _{CHG}	Current in charge mode, BAT		2	А
I _{DISCHG}	Current in discharge mode, BAT		4	А
R _{ISET}	Charge current programming resistor range	75		Ω
R _{ILIM}	Input current limit programming resistor range	105		Ω
TJ	Operating junction temperature range, T _J	0	125	°C

(1) The inherent switching noise voltage spikes should not exceed the absolute maximum rating on either the BOOT or SW pins. A *tight* layout minimizes switching noise.

THERMAL INFORMATION

	THERMAL METRIC ⁽¹⁾	bq24257	bq24258	UNITS
		YFF	RGE	UNITS
θ_{JA}	Junction-to-ambient thermal resistance	76.5	32.9	
θ_{JCtop}	Junction-to-case (top) thermal resistance	0.2	32.8	
θ_{JB}	Junction-to-board thermal resistance	44	10.6	°C/W
Ψյт	Junction-to-top characterization parameter	1.6	0.3	°C/W
Ψ _{JB}	Junction-to-board characterization parameter	43.4	10.7	
θ_{JCbot}	Junction-to-case (bottom) thermal resistance	N/A	2.3	

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.



bq24257 bq24258 SLUSBG0A - FEBRUARY 2013-REVISED MARCH 2013

www.ti.com

TYPICAL APPLICATION CIRCUITS

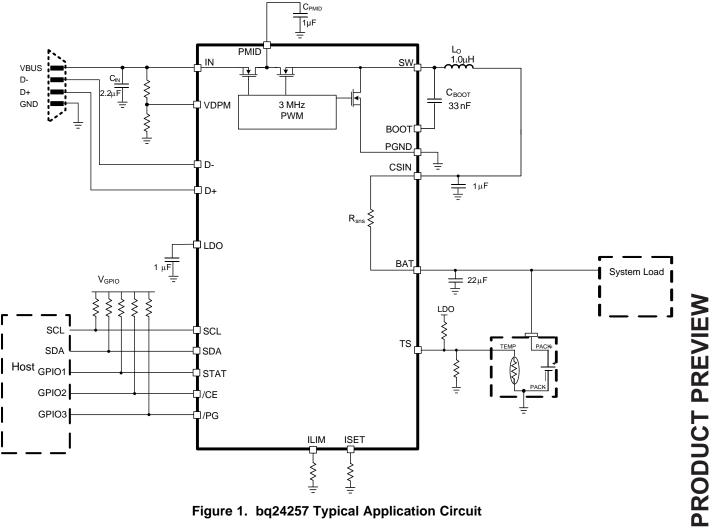
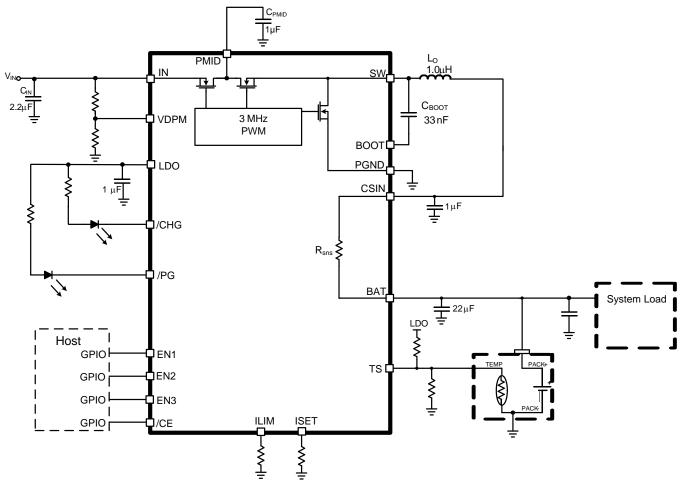


Figure 1. bq24257 Typical Application Circuit









ELECTRICAL CHARACTERISTICS

bq24257 App Circuit, $V_{UVLO} < V_{IN} < V_{OVP}$ AND $V_{IN} > V_{BAT} + V_{SLP}$, $T_J = 0^{\circ}C - 125^{\circ}C$ and $T_J = 25^{\circ}C$ for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
INPUT CURRE	ENTS					
		V_{UVLO} < V_{IN} < V_{OVP} and V_{IN} > V_{BAT} + $V_{SLP},$ PWM switching		10		mA
lin	Supply current from IN	V_{UVLO} < V_{IN} < V_{OVP} and V_{IN} > V_{BAT} + $V_{SLP},$ PWM not switching			5	ША
		0°C< T _J < 85°C, High-Z Mode			150	μA
	Battery discharge current in high impedance	0°C< T _J < 85°C, V _{BAT} = 4.2 V, VIN = 0 V or 5V, High-Z Mode		20	TBD	μA
IBAT_HIZ	mode, (BAT, SW, SYS)	0° C< T _J < 85°C, V _{BAT} = 4.2 V, VIN = 0V, SYSOFF Mode			1	μA
BATTERY CH	ARGER					
R _{SNS}	Internal battery charger MOSFET on- resistance	Measured from BAT to SYS, $V_{BAT} = 4.2V$ (WCSP only)		25	TBD	mΩ
	I ² C mode	Operating in voltage regulation, Programmable range	3.5		4.44	V
V _{BATREG}	SA mode			4.2		
		T _J = 25°C	-0.5%		0.5%	
	Voltage regulation accuracy	$T_J = 0^{\circ}C$ to 125°C	-0.75%		0.75%	
	Fast charge current range	$V_{LOWV} \le V_{BAT} < V_{BATREG}$	500		2000	mA
I _{CHG}	Fast charge current accuracy	I2C mode	-5%		5%	
K _{ISET}	Programmable fast charge current factor	$I_{CHG} = \frac{K_{ISET}}{R_{ISET}}$ (0.5A ≤ I _{CHG} < 2.0A)	-5%	TBD	5%	AΩ
VISET	Maximum ISET pin voltage (in regulation)			0.5		V
Vlowv		Battery voltage rising bq24257	2.9	3	3.1	V
VIUWV	Hysteresis for V _{LOWV}	Battery voltage falling		100		mV
I _{PRECHG}	Pr-charge current (V _{BATSHRT} < V _{BAT} < V _{LOWV})	Linear charging	8%	10%	12%	% I _{CHG}
V _{BAT_UVLO}	Battery under voltage lockout threshold	VBAT rising	2.37	2.5	2.63	V
	Battery UVLO hysteresis			100		mV
t _{DGL(LOWV)}	Deglitch time for pre-charge to fast charge transition			32		ms
V	Battery short threshold	Battery voltage rising	1.9	2	2.1	V
VBATSHRT	Hysteresis for V _{BATSHRT}	Battery voltage falling		100		mV
IBATSHRT	Trickle charge current (V _{BAT} < V _{BATSHRT})		20	30	40	mA
t _{DGL(BATSHRT)}	Deglitch time for battery short to fast-charge transition			32		ms
I _{TERM}	Termination current threshold	$25 \text{ mA} \le I_{\text{TERM}} < 100 \text{ mA}$ $100 \text{ mA} \le I_{\text{TERM}}$	-15% -10%		15% 10%	
t _{DGL(TERM)}	Deglitch time for charge termination	Both rising and falling, 2-mV over-drive, t _{RISE} , t _{FALL} = 100 ns		32		ms
V _{RCH}	Recharge threshold voltage	Below V _{BATREG}	100	120	150	mV
t _{DGL(RCH)}	Deglitch time	V_{BAT} falling below V_{RCH} , $t_{FALL} = 100$ ns		32		ms
IDETECT	Battery detection current before charge done (sink current) ⁽¹⁾	Termination enabled		2.5		mA
t _{DETECT}	Battery detection time	Termination enabled		250		ms
T _{safe}	Safety Timer Accuracy		-20%		20%	

(1) NO NOTE IN THE SOURCE ?

Copyright © 2013, Texas Instruments Incorporated



ELECTRICAL CHARACTERISTICS (continued)

bq24257 App Circuit, $V_{UVLO} < V_{IN} < V_{OVP}$ AND $V_{IN} > V_{BAT} + V_{SLP}$, $T_J = 0^{\circ}C - 125^{\circ}C$ and $T_J = 25^{\circ}C$ for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
BATTERY CH	ARGER LiFePO4 (bq24258)					
V _{REG-OVCHG}	Over charge voltage regulation		3.76	3.8	3.84	V
V _{FLT-CHG}	Float charge regulation		3.46	3.5	3.54	V
V _{OVCHG}	Overcharge comparator for LiFePo	V _{BAT} rising	3.65	3.7	3.75	V
V _{OVCHG-HYS}		V _{BAT} falling		300		mV
t _{DGL(OVCHG)}	Deglitch on the overcharge comparator			32		ms
INPUT PROTE	ECTION					
		ENx=010 or IN_LIMIT_x=000	90	95	100	
		ENx=000 or IN_LIMIT_x=010	450	475	500	mA
I _{IN}	Input current limiting	ENx=x10 or IN_LIMIT_x=110	I _{LIM}	$= \frac{K_{ILIM}}{R_{ILIM}}$		
I _{LIM}	Maximum input current limit programmable range for IN input	ENx=x10 or IN_LIMIT_x=110	500		2000	mA
K _{ILIM}	Maximum input current factor for IN input	I _{LIM} = 500 mA to 2.0 A	-10%	TBD	10%	AΩ
V _{ILIM}	Maximum ILIM pin voltage (in regulation)			TBD		V
	\/ threshold repres	SA mode	4.2		10	V
V _{IN_DPM}	V _{IN_DPM} threshold range	I ² C mode	4.2		4.76	V
	V _{IN_DPM} threshold accuracy	Both I2C and SA mode	-2		2	%
	IC active threshold voltage	V _{IN} rising	3.6	3.8	4.0	V
V _{UVLO}	IC active hysteresis	V _{IN} falling from above V _{UVLO}		150		mV
.,	Sleep-mode entry threshold, V _{SUPPLY-VBAT}	V _{IN} falling	0	40	100	mV
V _{SLP}	Sleep-mode exit hysteresis	V _{IN} rising	40	100	160	mV
t _{DGL(SLP)}	Deglitch time for supply rising above V _{SLP} +V _{SLP-EXIT}	Rising voltage, 2-mV over drive, t _{RISE} =100ns		32		ms
M	Input supply OVP threshold voltage	IN rising	6.2	6.5		V
V _{OVP}	V _{OVP} hysteresis	IN falling from V _{OVP}		100	6.8	mV
t _{DGL(OVP)}	Deglitch time for IN Rising above VOVP	IN rising voltage, t _{RISE} = 100ns		32		ms
V _{BOVP}	Battery OVP threshold voltage	VBAT threshold over V_{BATREG} to turn off charger during charge	102.5	105		% V _{BATRE}
	V _{BATOVP} hysteresis	Lower limit for V_{BAT} falling from above V_{BOVP}		100	107.5	
t _{DGL(BOVP)}	BOVP Deglitch	Battery entering/exiting BOVP		1		ms
PWM CONVE	RTER					
R _{ON(BLK)}	Internal blocking MOSFET on-resistance	Measured from IN to PMID		75		mΩ
R _{ON(HS)}	Internal high-side MOSFET on-resistance	Measured from IN to SW		85		mΩ
R _{ON(LS)}	Internal low-side MOSFET on-resistance	Measured from SW to PGND		95		mΩ
I _{CbC}	Cycle-by-cycle current limit	VSYS shorted		3.2		А
f _{OSC}	Oscillator frequency		2.7	3	3.3	MHz
D _{MAX}	Maximum duty cycle			95%		
D _{MIN}	Minimum duty cycle		0%			
	Thermal trip			150		
T _{SHTDWN}	Thermal hysteresis			10		°C
T _{REG}	Thermal regulation threshold	Charge current begins to cut off		125		
LDO						
V _{LDO}	LDO Output Voltage	VIN = 5.5V, ILDO = 0 to 50 mA		4.9		V
	· -		1			
I _{LDO}	Maximum LDO Output Current		50			mA



ELECTRICAL CHARACTERISTICS (continued)

bq24257 App Circuit, $V_{UVLO} < V_{IN} < V_{OVP}$ AND $V_{IN} > V_{BAT} + V_{SLP}$, $T_J = 0^{\circ}C - 125^{\circ}C$ and $T_J = 25^{\circ}C$ for typical values (unless otherwise noted)

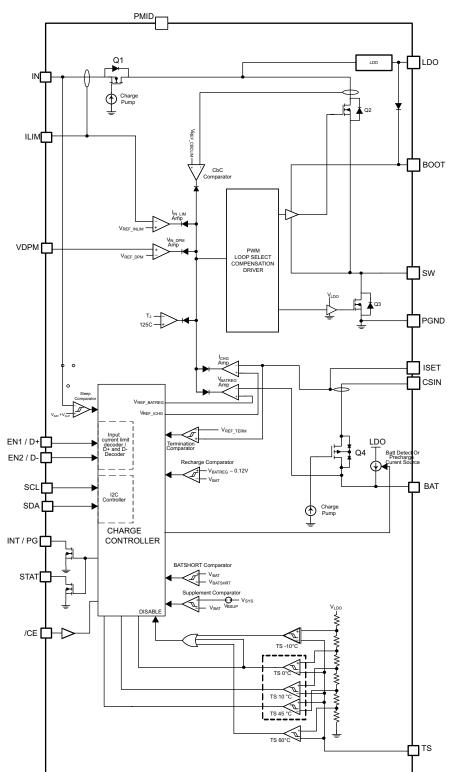
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BATTERY-PA	CK NTC MONITOR ⁽²⁾					
V _{HOT}	High temperature threshold	V _{TS} falling	29.6	30	30.4	%V _{LDO}
V _{HYS(HOT)}	Hysteresis on high threshold	VTS rising		1	1	
V _{WARM}	Warm temperature threshold	V _{TS} falling	37.9	38.3	38.7	0/\/
V _{HYS(WARM)}	Hysteresis on warm temperature threshold	V _{TS} rising		1		$%V_{LDO}$
V _{COOL}	Cool temperature threshold	VTS rising	56.5	56.5	56.9	0/\/
V _{HSY(COOL)}	Hysteresis on cool temperature threshold	V _{TS} falling		1		$%V_{LDO}$
V _{COLD}	Low temperature threshold	V _{TS} rising	59.6	60	60.4	0/\/
V _{HYS(COLD)}	Hysteresis on low threshold	V _{TS} falling		1		$%V_{LDO}$
V _{TS_DIS}	TS disable threshold		70		72	$%V_{LDO}$
R _{TS_DIS}	Internal Pull up for float disable	Measured from TS to LDO		1		MΩ
t _{DGL(TS)}	Deglitch time on TS change			50		ms
INPUTS (DBP	P, EN1, EN2, EN3, CE, SCL, SDA)	•	· · ·			
VIH	Input high threshold		1.3			V
V _{IL}	Input low threshold				0.4	V
STATUS OUT	PUTS (STAT, PG, CHG)		F			
V _{OL}	Low-level output saturation voltage	I _O = 5 mA, sink current			0.4	V
IIH	High-level leakage current	Hi-Z and 5V applies			1	mA
TIMERS		<u> </u>	ł		Į	
t _{SAFETY}	45 min safety timer			2700		S
	6 hr safety timer			21600		S
	9 hr safety timer			32400		s
t _{WATCH-DOG}	Watch dog timer			50		S
D+/D- DETEC	-					
I _{DP_SRC}	D+ current source for DCD	DCD	7		13	μA
R _{DM DWN}	D- pull-down resistance for DCD	DCD	14.25		24.8	kΩ
V _{DP_LOW}	D+ low comparator threshold for DCD	DCD	0.85	0.9	0.95	V
V _{DP SRC}	D+ source voltage for Primary Detection	Primary Detection	0.5	0.6	0.7	V
I _{DP_SRC_PD}	D+ source voltage output current for Primary Detection	Primary Detection	200			μA
I _{DM_SINK}	D– sink current for Primary Detection	Primary Detection	50	100	150	μA
V _{DAT_REF}	Primary Detection threshold	Primary Detection	250	325	400	mV
VLGC	Primary Detection threshold	Primary Detection	0.85	0.9	0.95	V
V _{DM SRC}	D- source voltage for Secondary Detection	Secondary Detection	0.5	0.6	0.7	V
I _{DM_SRC_PD}	D– source voltage output current for Secondary Detection	Secondary Detection	200			μA
I _{DP_SINK}	D+ sink current for Secondary Detection	Secondary Detection	50	100	150	μA
V _{DAT_REF}	Secondary Detection threshold	Secondary Detection	250	325	400	mV
VATT_LO	Apple/TomTom detection low threshold	Apple/TomTom Detection	1.7	1.8	1.9	V
V _{ATT_HI}	Apple/TomTom detection high threshold	Apple/TomTom Detection	3.15	3.25	3.35	V
AU_0		D– , switch open		4.5		pF
	Innut Consoltance	- , - , - , - , - , - , - , - , - , - ,		1.0		P
CI	Input Capacitance	D+ switch open		45		
Cı		D+, switch open D–, switch open	-1	4.5	1	μA

(2) NO NOTE IN THE SOURCE ?

TEXAS INSTRUMENTS

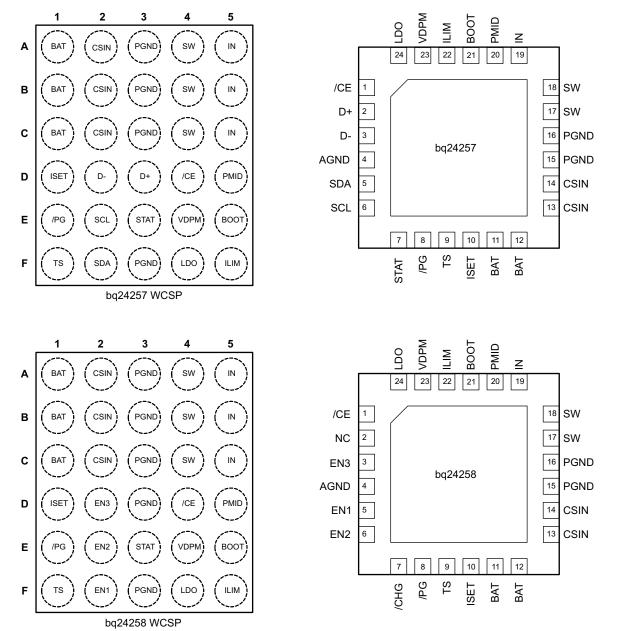
www.ti.com

BLOCK DIAGRAM





PIN OUTS



bq	24257	
bq	24258	

SLUSBG0A - FEBRUARY 2013 - REVISED MARCH 2013

www.ti.com

Texas Instruments

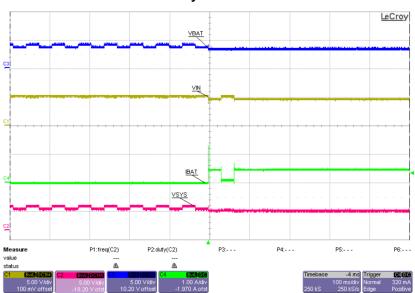
					FUNCT	
PIN NAME	bq24257	bq24257	bq24258	bq24258	I/O	DESCRIPTION
IN	YFF A5,B5,C5	RGE 19	YFF A5,B5,C5	RGE 19	1	Input power supply. IN is connected to the external DC supply (AC adapter or USB port). Bypass IN to PGND with >1 µF ceramic capacitor
PMID	D5	20	D5	20	I	Connection between blocking FET and high-side FET. Connect a 1 μF capacitor from PMID to PGND as close to the PMID and PGND pins as possible
SW	A4,B4,C4	17-18	A4,B4,C4	17-18	0	Inductor Connection. Connect to the switching side of the external inductor.
BOOT	E5	21	E5	21	I	High Side MOSFET Gate Driver Supply. Connect a 0.033 μF ceramic capacitor (voltage rating > 15 V) from BOOT to SW to supply the gate drive for the high side MOSFETs.
PGND	A3,B3,C3,F 3	15-16	A3,B3,C3, D3,F3	15-16		Power Ground terminal. Connect to the ground plane of the circuit. For QFN only, connect to the thermal pad of the IC.
CSIN	A2,B2,C2	13-14	A2,B2,C2	13-14	1	System Voltage Sense and SMPS output filter connection. Connect SYS to the system output at the output bulk capacitors. Bypass SYS locally with at least 10 $\mu F.$ SYS rail should have at least 20 μF total capacitance.
BAT	A1,B1,C1	11-12	A1,B1,C1	11-12	I/O	Battery Connection. Connect to the positive terminal of the battery. Additionally, bypass BAT with atleast $1\mu F$ capacitor to GND.
TS	F1	9	F1	9	I	Battery Pack NTC Monitor. Connect TS to the center tap of a resistor divider from LDO to GND. The NTC is connected from TS to GND. The TS function provides 4 thresholds for JEITA or PSE compatibility. See the NTC Monitor section for more details on operation and selecting the resistor values.
VDPM	E4	23	E4	23	I	Input DPM Programming Input. Connect a resistor divider between IN and GND with VDPM connected to the center tap to program the Input Voltage based Dynamic Power Management threshold (VIN_DPM). The input current is reduced to maintain the supply voltage at VIN_DPM. The reference for the regulator is 1.23 V. Short pin to GND if external resistors are not desired—this sets a default of 4.68 V for the input DPM threshold.
ISET	D1	10	D1	10	I	Charge Current Programming Input. Connect a resistor from ISET to GND to program the fast charge current.
ILIM	F5	22	F5	22	I	Input Current Limit Programming Input. Connect a resistor from ILIM to GND to program the input current limit for IN. The current limit is programmable from 0.5A to 1.8A. ILIM has no effect on the USB input. If an external resistor is not desired, short to GND for a 2 A default setting.
/CE	D4	1	D4	1	I	Charge Enable Active-Low Input. Connect CE to a high logic level to place the battery charger in standby mode.
EN1			F2	5	I	Input Current Limit Configuration Inputs. Use EN1, and EN2 to control the maximum input current and enable USB compliance. See Table 1 for programming details.
EN2			E2	6	I	
EN3			D2	3	I	
/PG	E1	8	E1	8	0	Power Good Open Drain Output. /PG is pulled low when a valid supply is connected to IN. A valid supply is between VBAT+VSLP and VOVP. If no supply is connected or the supply is out of this range, /PG is high impedance.
STAT	E3	7	E3	7	0	Status Output. STAT is an open-drain output that signals charging status and fault interrupts. STAT pulls low during charging. STAT is high impedance when charging is complete or the charger is disabled. When a fault occurs, a 256 μ s pulse is sent out as an interrupt for the host. STAT is enabled/disabled using the EN_STAT bit in the control register. STAT will indicate recharge cycles. Connect STAT to a logic rail using an LED for visual indication or through a 10 k Ω resistor to communicate with the host processor.
NC				2		Status Output. INT is an open-drain output that signals charging status and fault interrupts. INT pulls low during charging. INT is high impedance when charging is complete or the charger is disabled. When a fault occurs, a 256µs pulse is sent out as an interrupt for the host. INT will not indicate recharge cycle. Connect INT to a logic rail through a 10 k Ω resistor to communicate with the host processor.
SCL	E2	6			I	I^2C Interface Clock. Connect SCL to the logic rail through a 10 $k\Omega$ resistor.
SDA	F2	5			I/O	I^2C Interface Data. Connect SDA to the logic rail through a 10 k Ω resistor.



PIN FUNCTIONS (continued)

D+	D3	2			I	BC1.2 compliant D+/D- Based Adapter Detection. Detects DCP, SDP, and CDP. Also complies with the unconnected dead battery provision clause. D+ and D- are connected to the D+ and D- outputs of the USB port at power up. Also includes the detection of AppleTM and TomTomTM adapters where a 500mA input current limit is enabled.
D-	D2	3			I	
LDO	F4	24	F4	24	0	LDO output. LDO is regulated to 4.9 V and drives up to 50 mA. Bypass LDO with a 1 μ F ceramic Capacitor. LDO is enabled when VUVLO < VIN < VOVP.
AGND		4		4		Analog Ground for QFN only. Connect to the thermal pad and the ground plane of the circuit.

TYPICAL CHARACTERISTICS



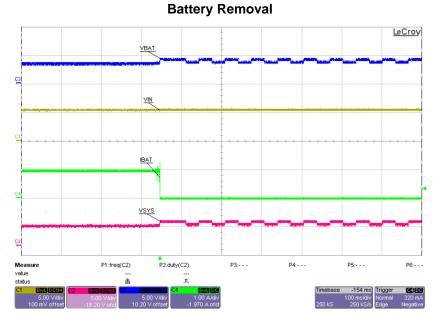
Battery Detection

Figure 3.

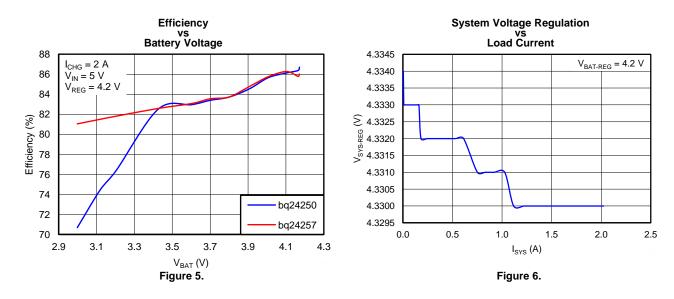
TEXAS INSTRUMENTS

www.ti.com

TYPICAL CHARACTERISTICS (continued)



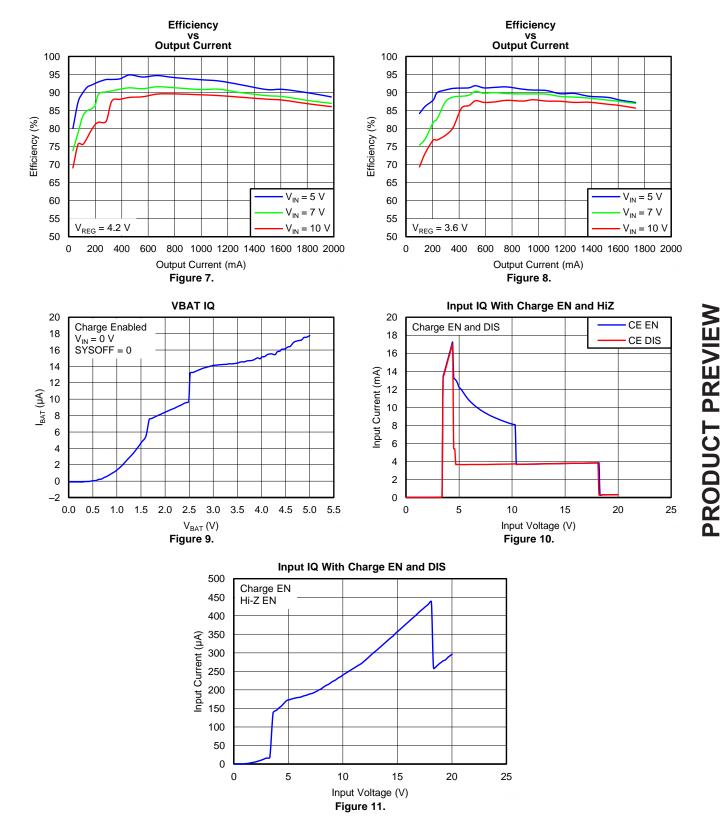




14 Submit Documentation Feedback



TYPICAL CHARACTERISTICS (continued)



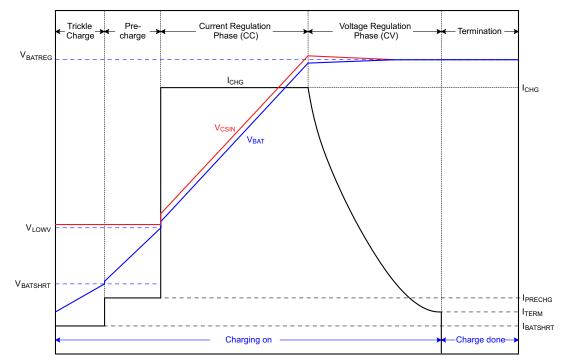


CHARGE PROFILE

The bq24257 family provides a switch-mode buck regulator with output non-power path and a charge controller to provide optimum performance over the full battery charge cycle. The control loop for the buck regulator has 6 primary feedback loops that can set the duty cycle:

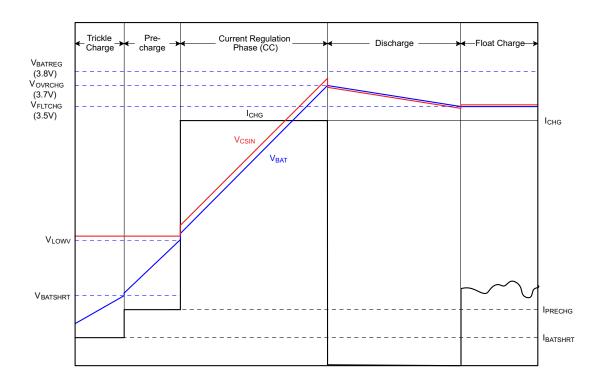
- 1. Constant Current (CC)
- 2. Constant Voltage (CV)
- 3. Input Current (I_{ILIM})
- 4. Input Voltage (V_{IN_DPM})
- 5. Die Temperature
- 6. Cycle by Cycle Current

The feedback with the minimum duty cycle will be chosen as the active loop. The bq24257 supports a precision Li-lon or Li-Polymer charging system for single-cell applications. The bq24257 includes an integrated charge sense resistor for highly accurate charge current sensing while reducing the external BOM requirements. The figure below illustrates a typical charge profile.



The bq24258 supports an advanced Lithium-Iron-Phosphate (LiFePO₄) algorithm. This allows for the charger to source the charge current up to the $V_{REG-OVCHG}$ level before entering the float charge region. See below for the charge profile characteristics:





EN1, EN2, EN3 Pins

If the D+/D- detection pins are not used (bq24257), input current limit pins are available for GPIO control. The EN1, EN2, and EN3 pin is available in the bq24258 spin to support USB 3.0 compliance. When the input current limit pins change state, the VIN_DPM threshold changes as well. See below for detailed truth table:

EN3	EN2	EN1	INPUT CURRENT LIMIT	VINDPM THRESHOLD
0	0	0	500mA	4.68V
0	0	1	Externally programmed by ILIM (up to 2.0A)	Externally programmed VDPM
0	1	0	100mA	4.36V
0	1	1	Input Hi-Z	None
1	0	0	900mA	4.68V
1	0	1	Externally programmed by ILIM (up to 2.0 A)	Externally programmed VDPM
1	1	0	150mA	4.36V
1	1	1	Input Hi-Z	None

(1) If EN3 = 0, it will be USB 2.0 compliant; If EN3 = 1, USB 3.0 compliant.

I2C and STAND ALONE OPERATION

The bq24257 series offers a unique feature when compared to traditional host mode chargers—the default input current limit, output current limit and VIN_DPM parameters can be set via external resistors. In traditional host mode chargers, the default parameters are programmed during manufacturing to set the i2c registers at a specific default. If an end application calls for an alternate default setting, the traditional charger is left with the only option of changing the parameters at the manufacturing stage. This may not always be acceptable.

Figure 12 illustrates the behavior of the bq24257 when transitioning between i2c mode and stand alone mode (except for the bq24257).

TEXAS INSTRUMENTS

www.ti.com

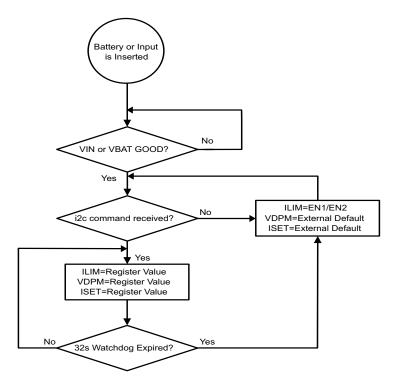


Figure 12. I2C and Stand Alone Mode Handoff

Once the battery or input is inserted and above the good thresholds, the device will determines if an i2c command has been received in order to discern whether to operate from the i2c registers or the external settings. Note that the bq24257 does not have EN1/EN2 pins and therefore the input current limit will be based on the D+/D- results. When in host mode (i2c operation), the device will enter stand alone operation once the watchdog timer expires.

External settings: ISET, ILIM and VIN_DPM

The fast charge current resistor (R_{ISET}) can be set by using the following formula:

$$\mathsf{R}_{\mathsf{ISET}} = \frac{\mathsf{K}_{\mathsf{ISET}}}{\mathsf{I}_{\mathsf{FC}}} = \frac{250}{\mathsf{I}_{\mathsf{FC}}} \tag{1}$$

Where I_{FC} is the desired fast charge current setting in Amperes.

The input current limit resistor (R_{ILIM}) can be set by using the following formula:

$$\mathsf{R}_{\mathsf{ILIM}} = \frac{\mathsf{K}_{\mathsf{ILIM}}}{\mathsf{I}_{\mathsf{IC}}} = \frac{270}{\mathsf{I}_{\mathsf{IC}}} \tag{2}$$

Where IIC is the desired input current limit in Amperes.

Based on the application diagram reference designators, the resistor R_1 and R_2 can be calculated as follows to set V_{IN_DPM} :

$$V_{\text{IN}_{\text{DPM}}} = V_{\text{REF}_{\text{DPM}}} \times \frac{R_1 + R_2}{R_2} = 1.23 \times \frac{R_1 + R_2}{R_2}$$
(3)

 V_{IN_DPM} should be chosen first along with R₁. Choosing R₁ first will ensure that R₂ will be greater than the resistance chosen. This is the case since V_{IN_DPM} should be chosen to be greater than 2x V_{REF_DPM} .

If resistors are not desired for BOM count reduction, the VDPM and the ILIM pins can be shorted to set the internal defaults. However, the ISET resistor must be populated as this will be interpreted as a fault. Table 2 summarizes the settings when the ILIM, ISET, and $V_{IN DPM}$ pins are shorted.

·-/



Table 2. ILIM, VDPM, and ISET Short Behaviors

PIN SHORTED	BEHAVIOR
ILIM	Input current limit = 2A
VDPM	$V_{IN_DPM} = 4.68V$
ISET	Fault—Charging Suspended

BC1.2 D+/D- DETECTION

The bq24257 includes a fully BC1.2 compliant D+/D- source detection. This detection supports the following types of ports:

- DCP (dedicated charge port)
- CDP (charging downstream port)
- SDP (standard downstream port)
- Apple[™]/TomTom[™] ports

This D+/D- detection algorithm does not support ACA (accessory charge adapter) identification, but the input current will default to 500mA when a charge port is attached to the ACA and bq24257 is connected to the OTG port.

The D+/D– detection algorithm is only active when the device is in standalone mode (e.g. the host is not communicating with the device and the watch dog timer has expired). However, when the device is in host mode (that is, host is communicating via i2c to the device) writing a '1' to register 0x04 bit location 4 (DPDM_EN) forces the device to perform a D+/D– detection on the next power port insertion. This allows the D+/D– detection to be enabled in both host mode and default mode.

The D+/D- detection algorithm has 5 primary states. These states are termed the following:

- 1. Data Contact Detect
- 2. Primary Detection
- 3. Secondary Detection
- 4. Non-standard Adapter Detection (for Apple[™] / TomTom[™])
- 5. Detection Configuration

The DCD state determines if the device has properly connected to the D+/D− lines. If the device is not in host mode and VBUS is inserted (or DPDM_EN is true) the device will enter the DCD state and enable the appropriate algorithm. If the DCD timer expires, the device will enter the Non-standard Adapter Detection (for Apple[™] / TomTom[™]) state. Otherwise it will enter the Primary Detection state.

When entering the Primary Detection state, the appropriate algorithm is enabled to determine whether to enter the secondary detection state for DCP and CDP or the secondary detection state for SDP/Non-Standard adaptors.

The non-standard adapter detection state for Apple[™] / TomTom[™] tests for the unique conditions for these nonstandard adapters. If the algorithm passes the unique conditions found with these adapters, it will proceed to the Detection Configuration state. Otherwise it will revert back to the primary detection state.

The secondary detection state determines whether the input port is a DCP, CDP, SDP, or other non-standard adapters. If the Primary Detection state indicated that the input port is either a DCP or CDP, the device will enable the appropriate algorithm to differentiate between the two. If the Primary Detection state indicated that the input port is either a SDP or non-standard adapter, the device will enable the appropriate algorithm to differentiate between the two will enable the appropriate algorithm to differentiate between the device will enable the appropriate algorithm to differentiate between the device will enable the appropriate algorithm to differentiate between the device will continue to the Detection Configuration state.

bq24257 bq24258 TEXAS INSTRUMENTS

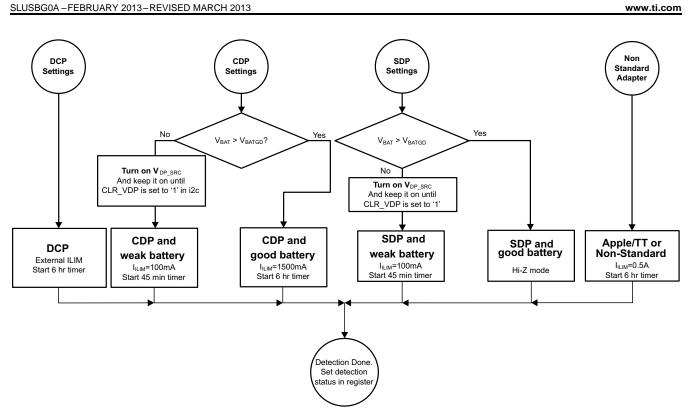


Figure 13. Detection Configuration State

The detection configuration state sets the input current limit of the device along with the charge timer. The exception to the CDP and the SDP settings are due to the Dead Battery Provision (DBP) clause for unconnected devices. This clause states that the device can pull a maximum of 100mA when not connected due to a dead battery. During the battery wakeup time, the device sources a voltage on the D+ pin in order to comply with the DBP clause. Once the battery is good, the system can clear the D+ pin voltage by writing a '1' to address 0x07 bit position 4 (CLR_VDP). The device must connect to the host within 1sec of clearing the D+ pin voltage per the DPB clause.

A summary of the input current limits and timer configurations for each charge port type are found in Table 3.

CHARGE PORT TYPE	INPUT CURRENT LIMIT	CHARGE TIMER
DCP	External ILIM	6 hours
CDP Dead Battery	100 mA	45 minutes
CDP Good Battery	1500 mA	6 hours
SDP Dead Battery	100 mA	45 minutes
SDP Good Battery	Hi-Z	N/A
Non-Standard	500 mA	6 hours

Table 3. D+/D– Detection Results per Charge Port Type

TRANSIENT RESPONSE

The bq24250/1/3 includes an advanced hybrid switch mode control architecture. When the device is regulating the charge current (fast-charge), a traditional voltage mode control loop is used with a Type-3 compensation network. However, the bq24250/1/3 switches to a current mode control loop when the device enters voltage regulation. Voltage regulation occurs in three charging conditions: 1) Minimum system voltage regulation (battery below MINSYS), 2) Battery voltage regulation ($I_{BAT} < I_{CHG}$), and 3) Charge Done ($V_{SYS} = V_{BAT} + 2.5\%$). This architecture allows for superior transient performance when regulating the voltage due to the simplification of the



compensation when using current mode control. The below transient response plot illustrates a 0 A to 2 A load step with 4.7 ms full cycle and 12% duty cycle. A 3.9 V Li-Ion battery is used. The input voltage is set to 5 V, charge current is set to 0.5 A and the input current is limited to 0.5 A. Note that a high line impedance input supply was used to indicate a realistic input scenario (adapter and cable). This is illustrated by the change in V_{IN} seen at the input of the IC.

The figure shows a ringing at both the input voltage and the input current. This is caused by the input current limit speed up comparator.

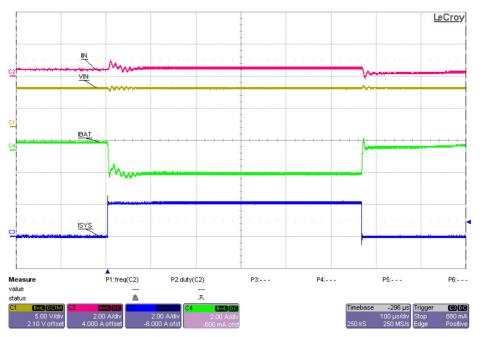


Figure 14. 2A Load step Transient

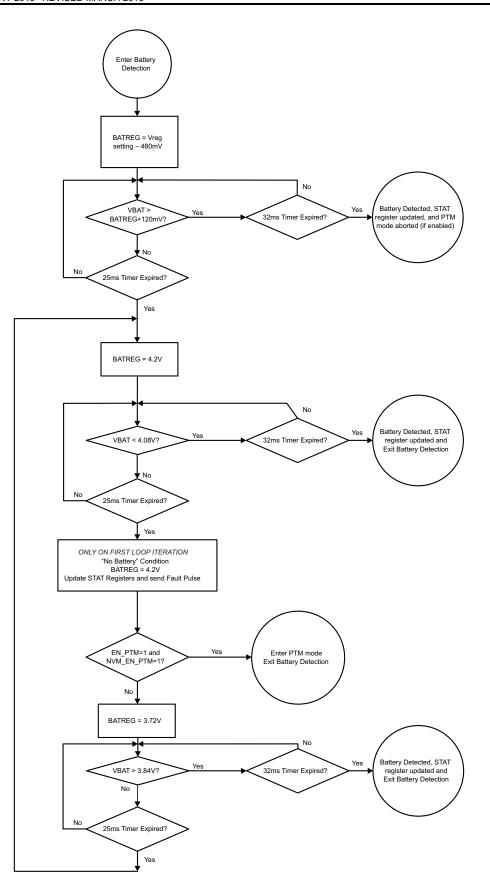
AnyBoot Battery Detection

The bq24257, bq24258 family includes a sophisticated battery detection algorithm used to provide the system with the proper status of the battery connection. The AnyBoot battery algorithm also guarantees the detection of voltage based battery protectors that may have a long closure time (due to the hysteresis of the protection switch and the cell capacity). The AnyBoot battery detection algorithm is utilizes a dual-voltage based detection methodology where the system rail will switch between two primary voltage levels. The period of the voltage level shift is 64ms and therefore the power supply rejection of the down-system electronics will see this shift as essentially DC.

The AnyBoot algorithm has essentially 3 states. The 1st state is used to determine if the device has terminated with a battery attached. If it has terminated due to the battery not being present, then the algorithm moves to the 2nd and 3rd states. The 2nd and 3rd states shift the system voltage level between 4.2V and 3.72V. In each state there are comparator checks to determine if a battery has been inserted. The two states guarantees the detection of a battery even if the voltage of the cell is at the same level of the comparator thresholds. The algorithm will remain in states 2 and 3 until a battery has been inserted. The flow diagram details for the Anyboot algorithm are shown in Figure 15.

TEXAS INSTRUMENTS

www.ti.com







NTC MONITOR (Contact Local TI Representative for function Availability)

Input Voltage Based DPM

During normal charging process, if the input power source is not able to support the programmed or default charging current, the supply voltage deceases. Once the supply drops to VIN_DPM (default 4.76 V), the input current limit is reduced down to prevent the further drop of the supply. When the IC enters this mode, the charge current is lower than the set. This feature ensures IC compatibility with adapters with different current capabilities without a hardware change.

Sleep Mode

The bq2425x enters the low-power sleep mode if the voltage on VIN falls below sleep-mode entry threshold, VBAT+VSLP, and VIN is higher than the under-voltage lockout threshold, VUVLO. This feature prevents draining the battery during the absence of VIN. When VIN < VBAT + VSLP, the bq2425x turns off the PWM converter, turns the battery FET, sends a single 256 μ s pulse is sent on the STAT and INT outputs and the FAULT/STAT bits of the status registers are updated in the I2C. Once VIN > VBAT + VSLP with the hysteresis, the FAULT bits are cleared and the device initiates a new charge cycle.

Input Over-Voltage Protection

The bq2425x provides over-voltage protection on the input that protects downstream circuitry. The built-in input over-voltage protection to protect the device and other components against damage from over voltage on the input supply (Voltage from VIN to PGND). When VIN > VOVP, the bq2425x turns off the PWM converter, turns the battery FET, sends a single 256 μ s pulse is sent on the STAT and INT outputs and the FAULT/STAT bits of the status registers and the battery/supply status registers are updated in the I2C. Once the OVP fault is removed, the FAULT bits are cleared and the device returns to normal operation. The OVP threshold for the bq2425x is programmable from 6.5 V to 10.5 V using VOVP bits in register #7.

The bq24257 includes the integration of an NTC monitor pin that complies with the Jeita specification (PSE also available upon request). The voltage based NTC monitor allows for the use of any NTC resistor with the use of the circuit shown below:

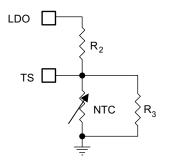


Figure 16. Voltage Based NTC Circuit

The use of R3 is only necessary when the NTC does not have a beta near 3500K. When deviating from this beta, error will be introduced in the actual temperature trip thresholds. The trip thresholds are summarized below which are typical values provided in the specification table.

V _{HOT}	30.0%
V _{WARM}	38.3%
V _{COOL}	56.5%
V _{COLD}	60%

bq24257 bq24258 SLUSBG0A – FEBRUARY 2013 – REVISED MARCH 2013

NSTRUMENTS

www.ti.com

(4)

When sizing for R2 and R3, it is best to solve two simultaneous equations that ensure the temperature profile of the NTC network will cross the V_{HOT} and V_{COLD} thresholds. The accuracy of the V_{WARM} and V_{COOL} thresholds will depend on the beta of the chosen NTC resistor. The two simultaneous equations are shown below:

$$%V_{COLD} = \frac{\left(\frac{R_{3}R_{NTC}|_{TCOLD}}{R_{3} + R_{NTC}|_{TCOLD}}\right)}{\left(\frac{R_{3}R_{NTC}|_{TCOLD}}{R_{3} + R_{NTC}|_{TCOLD}}\right) + R2} \times 100$$
$$%V_{HOT} = \frac{\left(\frac{R_{3}R_{NTC}|_{THOT}}{R_{3} + R_{NTC}|_{THOT}}\right)}{\left(\frac{R_{3}R_{NTC}|_{THOT}}{R_{3} + R_{NTC}|_{THOT}}\right) + R2} \times 100$$

Where the NTC resistance at the V_{HOT} and V_{COLD} temperatures must be resolved as follows:

$$R_{NTC}|_{TCOLD} = R_{o} e^{\beta \left(\frac{1}{T}COLD^{-1}T_{o}\right)}$$

$$R_{NTC}|_{THOT} = R_{o} e^{\beta \left(\frac{1}{T}HOT^{-1}T_{o}\right)}$$
(5)

To be Jeita compliant, T_{COLD} must be 0°C and T_{HOT} must be 60°C. If an NTC resistor is chosen such that the beta is 4000K and the nominal resistance is 10k Ω , the following R2 and R3 values result from the above equations:

 $R_2 = 5 k\Omega$ $R_3 = 9.82 k\Omega$

Figure 17 illustrates the temperature profile of the NTC network with R_2 and R_3 set to the above values.

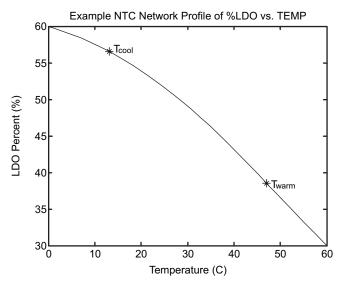


Figure 17. Voltage Based NTC Circuit Temperature Profile

For Jeita compliance, the T_{COOL} and T_{WARM} levels are to be 10°C and 45°C respectively. However, there is some error due to the variation in beta from 3500K. As shown above, the actual temperature points at which the NTC network crosses the V_{COOL} and V_{WARM} are 13°C and 47°C respectively. This error is small but should be considered when choosing the final NTC resistor.

Once the resistors are configured, the internal Jeita algorithm will apply the below profile at each trip point for battery voltage regulation and charge current regulation.



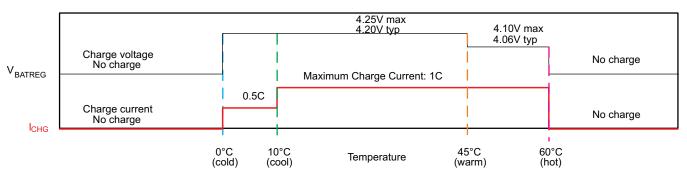


Figure 18. Jeita Profile for Voltage and Current Regulation Loops

PRODUCTION TEST MODE

To aid in end mobile device product manufacturing, the bq24257 includes a Production Test Mode (PTM), where the device is essentially a DC-DC buck converter. In this mode the input current limit to the charger is disabled and the output current limit is limited only by the inductor cycle-by-cycle current (e.g. 3.5A). The PTM mode can be used to test systems with high transient loads such as GSM transmission without the need of a battery being present.

As a means of safety, the Anyboot algorithm will determine if a battery is not present at the output prior to enabling the PTM mode. If a battery is present and the software attempts to enter PTM mode, the device will not enable PTM mode.

Fault Modes

The bq2425x family includes several hardware fault detections. This allows for specific conditions that could cause a safety concern to be detected. With this feature, the host can be alleviated from monitoring unsafe charging conditions and also allows for a "fail-safe" if the host is not present. Table 5 summarizes the faults that are detected and the resulting behavior.

Fault Condition	Charger Behavior	Safety Timer Behavior
Input OVP	VSYS and ICHG Disabled	Suspended
Input UVLO	VSYS and ICHG Disabled	Reset
Sleep (VIN < VBAT)	VSYS and ICHG Disabled	Suspended
TS Fault (Batter Over Temp)	VSYS Active and ICHG Disabled	Suspended
Thermal Shutdown	VSYS and ICHG Disabled	Suspended
Timer Fault	VSYS Active and ICHG Disabled	Reset
No Battery	VSYS Active and ICHG Disabled	Suspended
ISET Short	VSYS Active and ICHG Disabled	Suspended
LDO Short	VSYS and ICHG Disabled	Suspended

Table 5. Fault Condition

Safety Timer

At the beginning of charging process, the bq24257 starts the safety timer. This timer is active during the entire charging process. If charging has not terminated before the safety timer expires, the IC enters suspend mode where charging is disabled. The safety timer time is selectable using the I2C interface. A single 256µs pulse is sent on the STAT and INT outputs and the FAULT/ bits of the status registers are updated in the I2C.

Watchdog Timer

In addition to the safety timer, the bq24257 contains a 15-second watchdog timer that monitors the host through the I2C interface. Once a write is performed on the I2C interface, a watchdog timer is reset and started. The watchdog timer can be disabled by writing "0" on WD_EN bit of register #1. Writing "1" on that bit enables it and reset the timer.

Copyright © 2013, Texas Instruments Incorporated



If the watchdog timer expires, the IC enters DEFAULT mode where the default charge parameters are loaded and charging continues. The I2C may be accessed again to re-initialize the desired values and restart the watchdog timer as long as the safety timer has not expired. Once the safety timer expires, charging is disabled. This function prevents continuous charging of a defective battery if the host fails to reset the safety timer.

Thermal Regulation and Thermal Shutdown

During the charging process, to prevent overheat of the chip, bq2425x monitors the junction temperature, TJ, of the die and begins to taper down the charge current once T_J reaches the thermal regulation threshold, TREG. The charge current is reduced when the junction temperature increases about above TREG. Once the charge current is reduced, the system current is reduced while the battery supplements the load to supply the system. This may cause a thermal shutdown of the IC if the die temperature rises too. At any state, if T_J exceeds TSHTDWN, bq24260 suspends charging and disables the buck converter. During thermal shutdown mode, PWM is turned off, all timers are suspended, and a single 256 µs pulse is sent on the STAT and INT outputs and the FAULT/STAT bits of the status registers are updated in the I2C. A new charging cycle begins when T_J falls below TSHTDWN by approximately 10°C.



REGISTER MAPPING AND DESCRIPTION

Register #1

Memory location: 00, Reset state: x0xx xxxx

BIT	NAME	Read/Write	FUNCTION	
B7(MSB)	WD_FAULT	Read only	Read: 0 – No fault 1 – WD timeout if WD enabled	
B6	WD_EN	Read/Write	0 – Disable 1 – Enable (also resets WC timer)	
B5	STAT_1	Read only	00 – Ready	
B4	STAT_0	Read only	01 – Charge in progress 10 – Charge done 11 – Fault	
B3	FAULT_3	Read only	0000 – Normal	
B2	FAULT_2	Read only	0001 – Input OVP	
B1	FAULT_1	Read only	0010 – Input UVLO 0011 – Sleep	
B0(LSB)	FAULT_0	Read only	 0011 – Sleep 0100 – Battery Temperature (TS) Fault 0101 – Battery OVP 0110 – Thermal Shutdown 0111 – Timer Fault 1000 – No Battery connected 1001 – ISET short 1010 – LDO short 	

WD_FAULT – '0' indicates no watch dog fault has occurred, where a '1' indicates a fault has previously
occurred.

- WD_EN Enables or disables the internal watch dog timer. A '1' enables the watch dog timer and a '0' disables it.
- **STAT** Indicates the charge controller status
- **FAULT** Indicates the faults that have occurred. If multiple faults occurred, they can be read by sequentially addressing this register (e.g. reading the register 2 or more times). Once all faults have been read and the device is in a non-fault state, the fault register will show "Normal."

bq24257 bq24258

SLUSBG0A-FEBRUARY 2013-REVISED MARCH 2013



www.ti.com

Register #2

Memory location: 01, Reset state: 1010 1100

BIT	NAME	Read/Write	FUNCTION	
B7(MSB)	Reset	Write only	Write: 1 – Reset all registers to default values 0 – No effect	
B6	I _{IN_ILIMIT_2}	Read/Write	000 – USB2.0 host with 100mA current limit	
B5	I _{IN_ILIMIT_1}	Read/Write	001 – USB3.0 host with 150mA current limit	
B4	I _{IN_} ILIMIT _0	Read/Write	 010 – USB2.0 host with 500mA current limit 011 – USB3.0 host with 900mA current limit 100 – Charger with 1500mA current limit 101 – Charger with 2000mA current limit 110 – External ILIM current limit(5) 111- No input current limit with internal clamp at 3A (PTM MODE) 	
B3	EN_STAT	Read/Write	0 – Disable STAT function 1 – Enable STAT function	
B2	EN_TERM	Read/Write	0 – Disable charge termination 1 – Enable charge termination	
B1	CE	Read/Write	0 – Charging is enabled 1 – Charging is disabled	
B0(LSB)	HZ_MODE	Read/Write	0 – Not high impedance mode 1 – High impedance mode	

- I_{IN_LIMIT} Sets the input current limit level. When in host mode this register sets the regulation level. However, when in standalone mode (e.g. no i2c writes have occurred after power up or the WD timer has expired) the external resistor setting for IILIM sets the regulation level.
- **EN_STAT** Enables and disables the STAT pin. When set to a '1' the STAT pin is enabled and function normally. When set to a '0' the STAT pin is disabled and the open drain FET is in HiZ mode.
- **EN_TERM** Enables and disables the termination function in the charge controller. When set to a '1' the termination function will be enabled. When set to a '0' the termination function will be disabled. When termination is disabled, there are no indications of the charger terminating (i.e. STAT pin or STAT registers).
- CE The charge enable bit which enables or disables the charge function. When set to a '0', the charger operates normally. When set to a '1', the charger is disables by turning off the BAT FET between SYS and BAT. The SYS pin continues to stay active via the switch mode controller if an input is present.
- **HZ_MODE** Sets the charger IC into low power standby mode. When set to a '1', the switch mode controller is disabled but the BAT FET remains ON to keep the system powered. When set to a '0', the charger operates normally.

Register #3

Memory location: 02, Reset state: 1000 1111

BIT	NAME	Read/Write	FUNCTION	
B7(MSB)	V _{BATREG_5} ⁽¹⁾	Read/Write	Battery Regulation Voltage: 640mV (default 1)	
B6	V _{BATREG_4} ⁽¹⁾	Read/Write	Battery Regulation Voltage: 320mV (default 0)	
B5	V _{BATREG_3} ⁽¹⁾	Read/Write	Battery Regulation Voltage: 160mV (default 0)	
B4	V _{BATREG_2} ⁽¹⁾	Read/Write	Battery Regulation Voltage: 80mV (default 0)	
B3	V _{BATREG_1} ⁽¹⁾	Read/Write	Battery Regulation Voltage: 40mV (default 1)	
B2	V _{BATREG_0} ⁽¹⁾	Read/Write	Battery Regulation Voltage: 20mV (default 1)	
B1 ⁽⁴⁾⁽⁵⁾	USB_DET_1/EN1	Read Only	Return USB detection result or pin EN1/EN0 status -	
B0(LSB)	USB_DET_0/EN0	Read Only	00 – DCP detected / EN1=0, EN0=0 01 – CDP detected / EN1=0, EN0=1 10 – SDP detected / EN1=1, EN0=0 11 – Apple/TT or non-standard adaptor detected/EN1=1, EN0=1	

(1) Charge voltage range is 3.5V—4.44V with the offset of 3.5V and step of 20mV (default 4.2V)

• V_{BATREG} – Sets the battery regulation voltage

 USB_DET/EN – Provides status of the D+/D– detection results for spins that include the D+/D– pins or the state of EN1/EN2 for spins that include the EN1/EN2 pins.

Register #4

Memory location: 03, Reset state: 0000 0000

BIT	NAME	Read/Write	FUNCTION	
B7(MSB)	I _{CHG_4} ⁽¹⁾⁽²⁾	Read/Write	Charge current 800mA – (default 0)	
B6	I _{CHG_3} ⁽¹⁾⁽²⁾	Read/Write	Charge current: 400mA – (default 0)	
B5	I _{CHG_2} ⁽¹⁾⁽²⁾	Read/Write	Charge current: 200mA – (default 0)	
B4	I _{CHG_1} ⁽¹⁾⁽²⁾	Read/Write	Charge current: 100mA – (default 0)	
B3	I _{CHG_0} ⁽¹⁾⁽²⁾	Read/Write	Charge current: 50mA – (default 0)	
B2	I _{TERM_2} ⁽³⁾	Read/Write	Termination current sense threshold: 100mA (default 0)	
B1	I _{TERM_1} ⁽³⁾	Read/Write	Termination current sense threshold: 50mA (default 0)	
B0(LSB)	$I_{\text{TERM}_0}^{(3)}$	Read/Write	Termination current sense threshold: 25mA (default 0)	

(1) Charge current offset is 500mA and default charge current is 500mA (maximum is 2.0A)

(2) When all bits are 1's, it is external ISET charging mode

(3) Termination threshold voltage offset is 50mA and default termination current is 50mA

• I_{CHG} – Sets the charge current regulation

• ITERM - Sets the current level at which the charger will terminate

bq24257 bq24258 SLUSBG0A – FEBRUARY 2013 – REVISED MARCH 2013

TEXAS INSTRUMENTS

www.ti.com

Register #5

Memory location: 04, Reset state: xx00 x110

BIT	NAME	Read/Write	FUNCTION
B7(MSB)	LOOP_STATUS1 ⁽¹⁾	Read Only	00 – No loop is active that slows down timer
B6	LOOP_STATUS0 ⁽¹⁾	Read Only	01 – V _{IN_DPM} regulation loop is active 10 – Input current limit loop is active 11 – Thermal regulation loop is active
B5	LOW_CHG	Read/Write	0 – Normal charge current set by 03h 1 – Low charge current setting 325mA (default 0)
B4	DPDM_EN	Read/Write	0 – Bit returns to 0 after D+/D– detection is performed 1 – Force D+/D– detection (default 0)
B3	CE_STATUS	Read Only	0 – CE low 1 – CE high
B2	VINDPM_2 ⁽²⁾	Read/Write	Input V _{IN-DPM} voltage: 320mV (default 1)
B1	VINDPM_1 ⁽²⁾	Read/Write	Input V _{IN-DPM} voltage: 160mV (default 1)
B0(LSB)	VINDPM_0 ⁽²⁾	Read/Write	Input V _{IN-DPM} voltage: 80mV (default 0)

(1) LOOP_STATUS bits show if there are any loop is active that slow down the safety timer. If a status occurs, these bits announce the status and do not clear until read. If more than one occurs, the first one is shown

(2) VIN-DPM voltage offset is 4.20V and default $V_{IN_{DPM}}$ threshold is 4.68V.

• LOOP_STATUS – Provides the status of the active regulation loop. The charge controller allows for only one loop can regulate at a time.

• LOW_CHG – When set to a '1', the charge current is reduced 325mA independent of the charge current setting in register 0x03. When set to '0', the charge current is set by register 0x03.

- DPDM_EN Forces a D+/D– detection routine to be executed once a '1' is written. This is independent of the input being supplied.
- CE_STATUS Provides the status of the CE pin level. If the CE pin is forced high, this bit returns a '1'. If the CE pin is forced low, this bit returns a '0'.

Register #6

Memory location: 05, Reset state: 101x 1xxx

BIT	NAME	Read/Write	FUNCTION
B7(MSB)	2XTMR_EN	Read/Write	0 – Timer not slowed at any time 1 – Timer slowed by 2x when in thermal regulation, VIN_DPM or DPPM (default 1)
B6	TMR_1	Read/Write	Safety Timer Time Limit
B5	TMR_2	Read/Write	00 – 0.75 hour fast charge 01 – 6 hour fast charge 10 – 9 hour fast charge 11 – Disable safety timers (default 01)
B4	SYSOFF	Read/Write	0 – SYSOFF disabled 1 – SYSOFF enabled
B2	TS_STAT2	Read only	TS Fault Mode:
B1	TS_STAT1	Read only	000 – Normal, No TS fault
B0(LSB)	TS_STAT0	Read only	 100 – TS temp < T_{COLD} (Charging suspended for JEITA and Standard TS) 101 – T_{FREEZE} < TS temp < T_{COLD} (Charging at 3.9V and 100mA and only for PSE option only) 110 – TS temp < T_{FREEZE} (Charging suspended for PSE option only) 111 – TS open (TS disabled)

2xTMR_EN – When set to a '1', the 2x Timer function is enabled and allows for the timer to be extended if a condition occurs where the charge current is reduced (i.e. _{VIN_DPM}, thermal regulation, etc.). When set to a '0', this function is disabled and the normal timer will always be executed independent of the current reduce conditions.

- SYSOFF When set to a '1' and the input is removed, the internal battery FET is turned off in order to reduce the leakage from the BAT pin to less than 1µA. Note that this disconnects the battery from the system. When set to a '0', this function is disabled.
- **TS_EN** Enables and disables the TS function. When set to a '1' the TS function is disabled otherwise it is enabled. Only applies to spins that have a TS pin.
- **TS_STAT** Provides status of the TS pin state for spins that have a TS pin.



Register #7

Memory location: 06, Reset state: 1110 0000

BIT	NAME	Read/Write	FUNCTION
B7(MSB)	V _{OVP_2}	Read/Write	OVP voltage:
B6	V _{OVP_1}	Read/Write	000 - 6.0V; 001 - 6.5V; 010 - 7.0V; 011 - 8.0V
B5	V _{OVP_0}	Read/Write	100 – 9.0V; 101 – 9.5V; 110 – 10.0V; 111 –10.5V
B4	CLR_VDP	Read/Write	0 – Keep D+ voltage source on during DBP charging
			1 – Turn off D+ voltage source to release D+ line
B3	FORCE_BATDET	Read/Write	0 – Enter the battery detection routine only if TERM is true or EN_PTM is true
			1 – Enter the battery detection routine
B2	FORCE_PTM	Read/Write	0 – PTM mode is disabled 1 – PTM mode is enabled if OTP_EN_PTM=1
B1	N/A	Read/Write	
B0(LSB)	N/A	Read/Write	

• V_{OVP} – Sets the OVP level

CLR_VDP – When the D+/D– detection has finished, some cases require the D+ pin to force a voltage of 0.6V. This bit allows the system to clear the voltage prior to any communication on the D+/D– pins. A '1' clears the voltage at the D+ pin if present.

• **FORCE_BATDET** – Forces battery detection and provides status of the battery presence. A logic '1' enables this function.

 FORCE_PTM – Puts the device in production test mode (PTM) where the input current limit is disabled. Note that a battery must not be present prior to using this function. Otherwise the function will not be allowed to execute. A logic '1' enables the PTM function.



APPLICATION INFORMATION

Inductor Selection

The inductor selection depends on the application requirements. The bq2425x is designed to operate at around 1 μ H. The value will have an effect on efficiency, and the ripple requirements, stability of the charger, package size, and DCR of the inductor. The 1 μ H inductor provides a good tradeoff between size and efficiency and ripple.

Once the inductance has been selected, the peak current is needed in order to choose the saturation current rating of the inductor. Make sure that the saturation current is always greater than or equal to the calculated I_{PEAK} . The following equation can be used to calculate the current ripple

 $\Delta I_{L} = \{VBAT (VIN - VBAT)\}/(VIN \times fs \times L)$

(6)

Then use current ripple to calculate the peak current as follows:

 $I_{PEAK} = I_{CHARGE} \times (1 + \Delta I_L/2)$

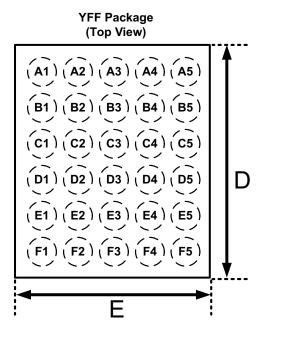
(7)

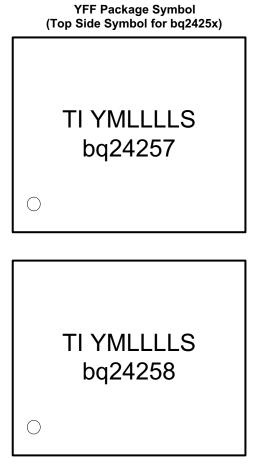
Layout Guidelines

- 1. Place the BOOT, PMID, IN, BAT, and LDO capacitors as close as possible to the IC for optimal performance.
- 2. Connect the inductor as close as possible to the SW pin, and the SYS/CSIN cap as close as possible to the inductor minimizing noise in the path.
- 3. Place a 1-µF PMID capacitor as close as possible to the PMID and PGND pins, making the high frequency current loop area as small as possible.
- 4. The local bypass capacitor from SYS/CSIN to GND must be connected between the SYS/CSIN pin and PGND of the IC. This minimizes the current path loop area from the SW pin through the LC filter and back to the PGND pin.
- 5. Place all decoupling capacitors close to their respective IC pins and as close as possible to PGND (do not place components such that routing interrupts power-stage currents). All small control signals must be routed away from the high-current paths.
- 6. To reduce noise coupling, use a ground plane if possible, to isolate the noisy traces from spreading its noise all over the board. Put vias inside the PGND pads for the IC.
- 7. The high-current charge paths into IN, Micro-USB, BAT, SYS/CSIN, and from the SW pins must be sized appropriately for the maximum charge current to avoid voltage drops in these traces.
- 8. For high-current applications, the balls for the power paths must be connected to as much copper in the board as possible. This allows better thermal performance because the board conducts heat away from the IC.



PACKAGE SUMMARY





0-Pin A1 Marker, TI-TI Letters, YM- Year Month Date Code, LLLL-Lot Trace Code, S-Assembly Site Code

The bq2425x devices are available in a 30-bump chip scale package (YFF, NanoFree™). The package dimensions are:

D - 2.427mm ±0.035mm

E - 2.027mm ±0.035mm

REVISION HISTORY

Changes from Original (February 2013) to Revision A

PRODUCT PREVIEW

Page



31-Mar-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
	(1)		Drawing		Qty	(2)		(3)		(4)	
BQ24257YFFR	PREVIEW	DSBGA	YFF	30	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM		BQ24257	
BQ24257YFFT	PREVIEW	DSBGA	YFF	30	250	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM		BQ24257	

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between

the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

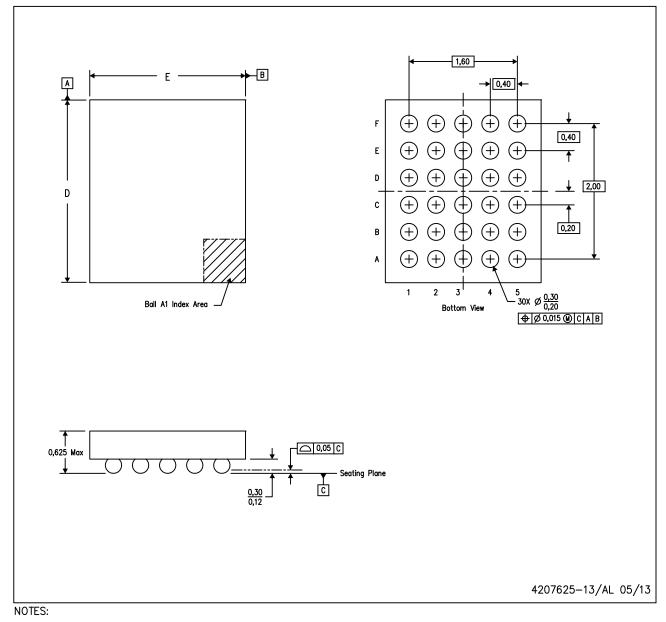
(4) Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

YFF (R-XBGA-N30)

DIE-SIZE BALL GRID ARRAY



A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. NanoFree™ package configuration.

NanoFree is a trademark of Texas Instruments



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products		Applications				
Audio	www.ti.com/audio	Automotive and Transportation	www.ti.com/automotive			
Amplifiers	amplifier.ti.com	Communications and Telecom	www.ti.com/communications			
Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers			
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps			
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy			
Clocks and Timers	www.ti.com/clocks	Industrial	www.ti.com/industrial			
Interface	interface.ti.com	Medical	www.ti.com/medical			
Logic	logic.ti.com	Security	www.ti.com/security			
Power Mgmt	power.ti.com	Space, Avionics and Defense	www.ti.com/space-avionics-defense			
Microcontrollers	microcontroller.ti.com	Video and Imaging	www.ti.com/video			
RFID	www.ti-rfid.com					
OMAP Applications Processors	www.ti.com/omap	TI E2E Community	e2e.ti.com			
Wireless Connectivity	www.ti.com/wirelessconnectivity					

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2013, Texas Instruments Incorporated